

Notice of References Cited	Application/Control No. 10/634,988	Applicant(s)/Patent Under Reexamination ITO ET AL.	
	Examiner Stacy A. Whitmore	Art Unit 2825	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0001885	01-2002	Noble, Wendell P.	438/149
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen, Yu et al., "Monte-Carlo algorithms for layout density control", January 2000, IEEE, pgs. 523-528.
	V	Kahng, A.B. et al., "New and exact filling algorithms for layout density control", January 1999, IEEE, pgs. 106-110.
	W	Kahng, A.B. et al., "Filling algorithms and analyses for layout density control", April 1999, IEEE, pgs. 445-462.
	X	Lee, Brian et al., "Using Smart dummy fill and selective reverse etchback for pattern density equalization", IEEE, pgs. 1-4.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.